

The Silicon Vertex Detector of the Belle II Experiment

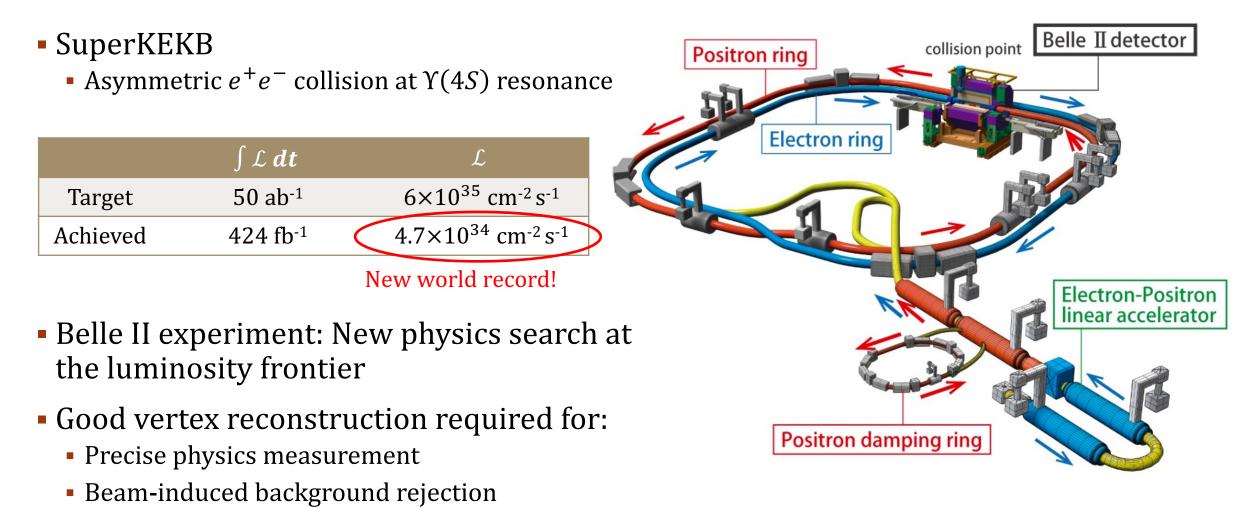
Wang Zihan 王子涵

U-Tokyo

on behalf of the Belle II SVD collaboration

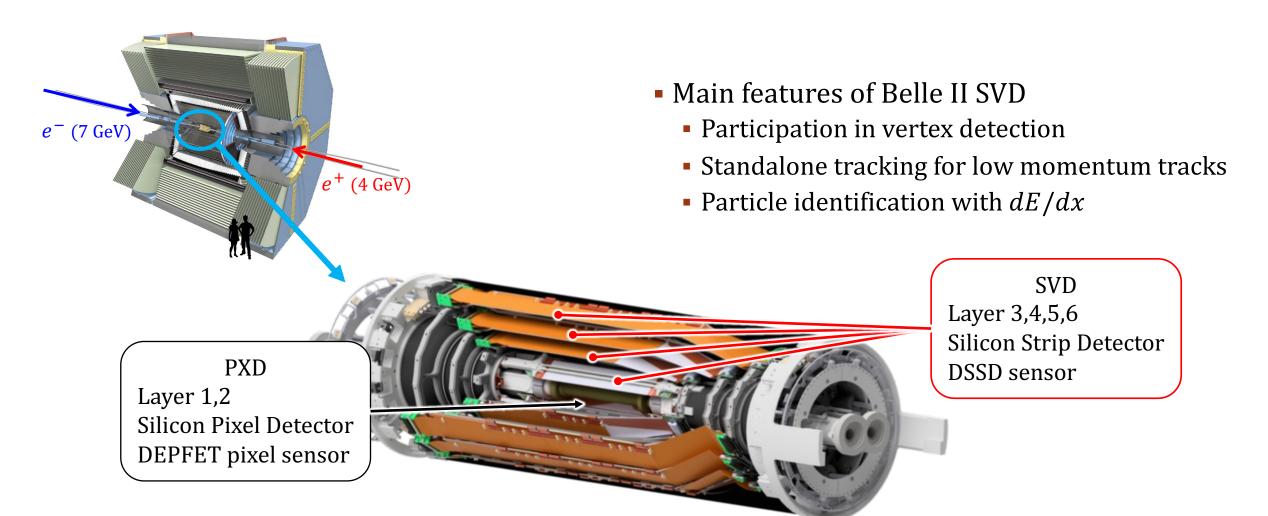
2023.09.04

SuperKEKB and Belle II Experiment



2

Belle II vertex detector (VXD)



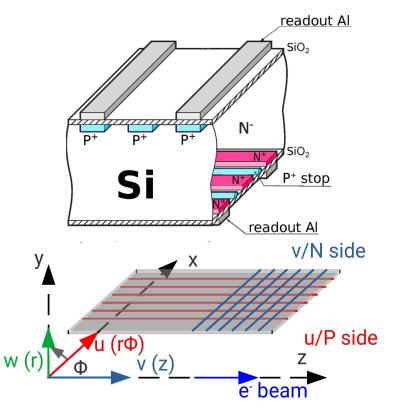


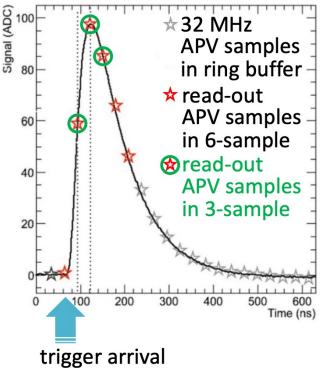
SVD sensors and front-end ASIC

- Double-sided Silicon Strip Detector (DSSD)
 - Provide 2-D spatial information
 - Depletion voltage: 20~60 V
 - Operation voltage: 100 V



- 128 channels per chip
- 50ns shaping time
- Radiation hardness > 100 Mrad
- Power consumption: 0.4 W/chip

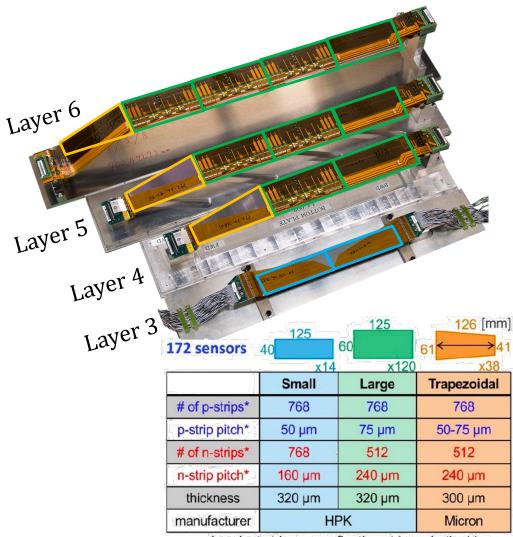




- 6 subsequent samples readout
- 3/6 mixed acquisition mode prepared for high luminosity runs

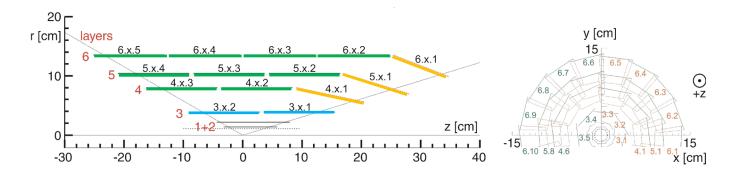


SVD structure



*readout strips - one floating strip on both sides

- DSSD sensors and APV25 ASICs are grouped into ladders
- 172 sensors, 1.2 m² sensor area, 224k readout strips
- Low material budget: 0.7% X₀/layer

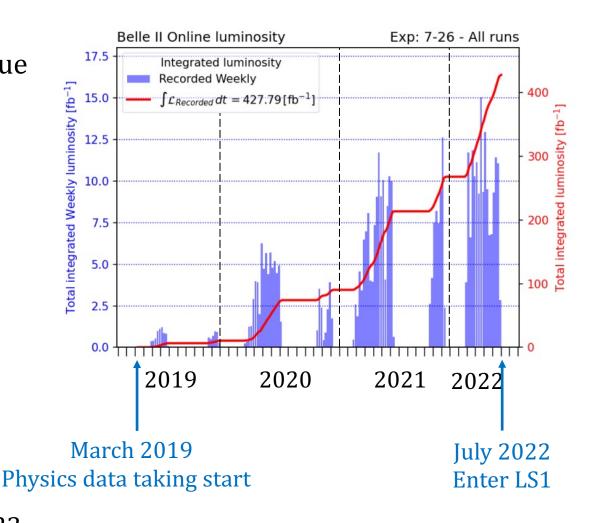


Layer	Ladders	Sensors /ladder	Radius [mm]
L3	7	2	39
L4	10	3	80
L5	12	4	104
L6	16	5	135



SVD operation

- Smooth and reliable operation without major issue
 - So far total masked strips < 1%
 - Stable environment and calibration constants evolution consistent with expectation
- Excellent detector performance!
 - Large hit efficiency (> 99%), precise position resolution and good signal-to-noise ratio (SNR)
- Background effects are well under control
- Enter Long Shutdown 1 (LS1) since July 2022
 - VXD upgrade with new PXD + current SVD
 - Planning to resume data taking from December 2023





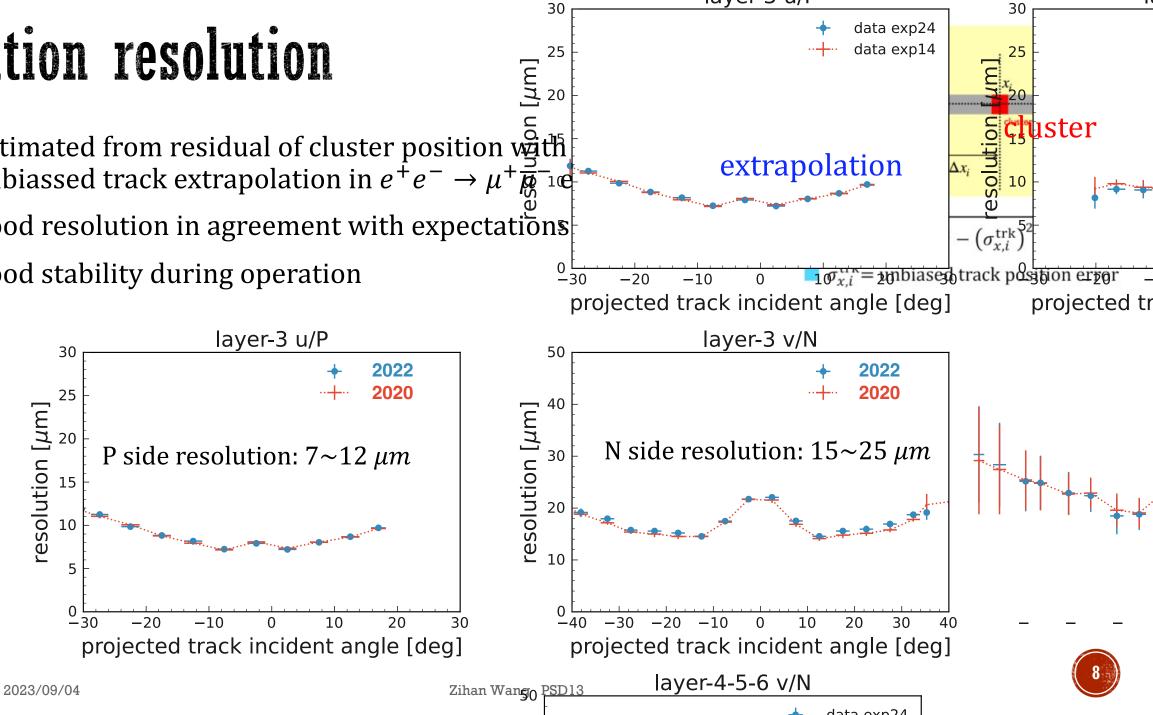
Highlights of the SVD performance



Position resolution

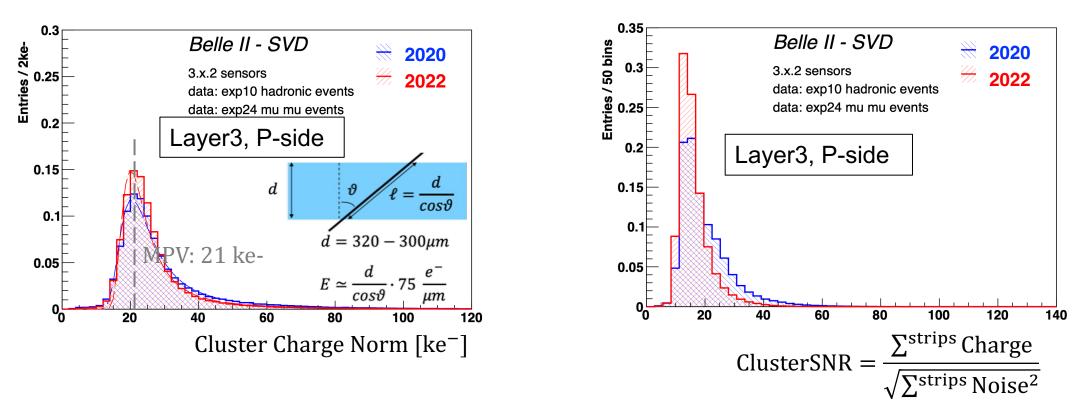
- Estimated from residual of cluster position with unbiassed track extrapolation in $e^+e^- \rightarrow \mu^+ \overline{p}_{\overline{p}}^{-1}e^{-1}$
- Good resolution in agreement with expectations
- Good stability during operation

resolution [µm]



layer-5 u/r

Cluster charge & SNR

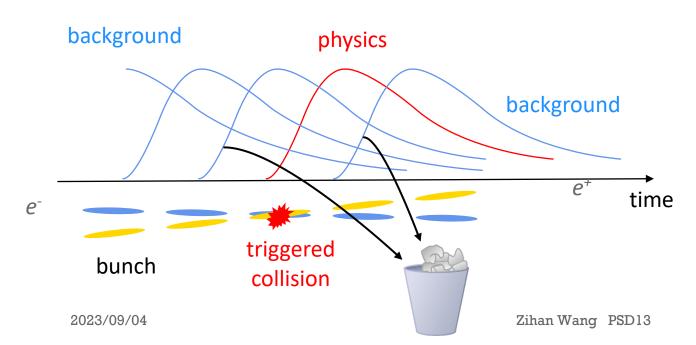


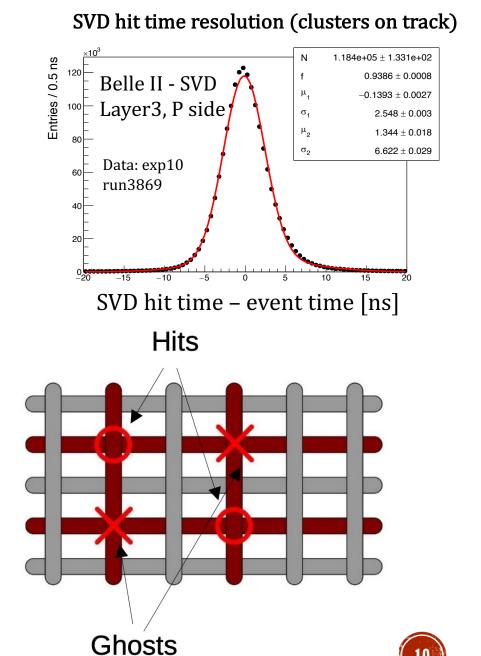
- Good stability of cluster charge and SNR from 2020 to 2022
 - Similar cluster charge, normalized to track length
 - Small SNR decrease due to increased noise from radiation damage
 - Still good SNR for all sensors, MPV ranging from 13~30 depending on sensor position and side



Hit time

- Excellent hit time resolution (< 3 ns) w.r.t event time
 - SuperKEKB bunch spacing: ~ 6 ns
 - Background hit interval ~ 100 ns
- Hit time selection can
 - Reject off-time beam background hits
 - Reduce wrong combination of P and N side clusters





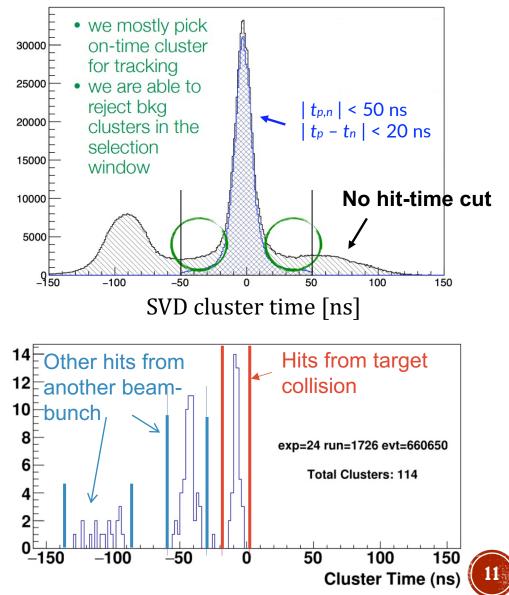
Background rejection with hit time

Selection on the SVD hit-time

- Selection based on <u>SVD hit-time</u> and <u>time difference</u> <u>between P and N side</u>
- Reject 50% off-time background hits and keep 99% tracking efficiency
- Allow to set the hit occupancy limit at layer 3 to 4.7% without tracking performance degradation

Cluster grouping

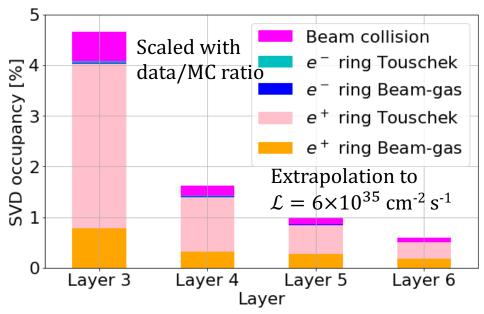
- Group clusters coming from the same collision using hittime event-by-event
- Use clusters from the same group for tracking
- With track time selection, further reduce the fake rate by 15%
- Increase the hit occupancy limit to 6%



Beam background effects on the SVD



Hit occupancy



- High occupancy could degrade tracking performance
- Current background level on layer 3 is less than 0.5% and well under control
- Extrapolation to target luminosity shows small safety margin w.r.t. 4.7% limit
 - With large uncertainty due to future machine evolution and possible interaction region re-design
 - Conservative extrapolation (8.7%) even exceeds 6% limit
- The small safety margin motivates vertex detector upgrade
 - See <u>Jerome's talk</u> for one of the upgrade options



Radiation effects (1)

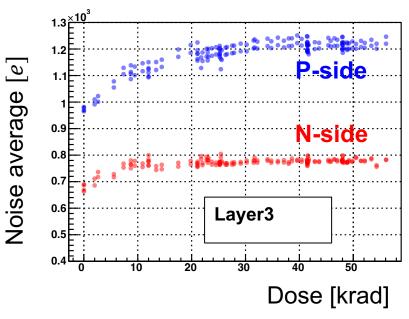
 Can deteriorate sensor performance increasing strip noise, leakage current & changing depletion voltage

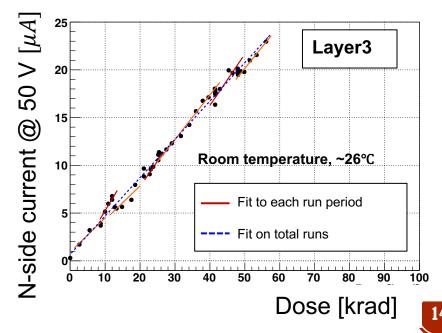
Strip noise

- Noise increase < 20% (30%) for N(P) side
 - Due to fixed oxide charges that increase interstrip capacitance
 - Expect to saturate

Leakage current

- Contribution to noise negligible now due to short APV25 shaping time
- Linear increase due to bulk damage by NIEL
- After 6 Mrad dose strip noise contribution from leakage current would reduce the Layer3 SNR < 10

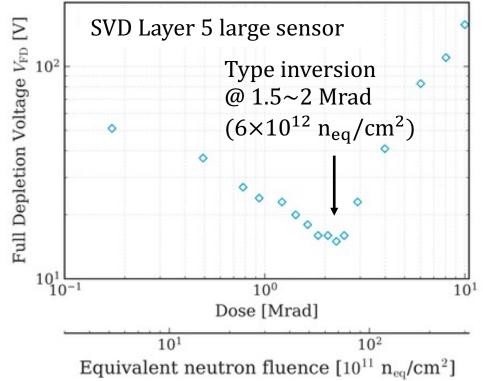




Radiation effects (2)

Depletion voltage

- Irradiation campaign up to 10 Mrad of a layer 5 sensor
 @ Tohoku Univ. in July 2022
 - 90 MeV *e*⁻ beam
- Confirmed SVD sensors work well even after type inversion
- Good charge collection efficiency confirmed with Sr90 source measurement

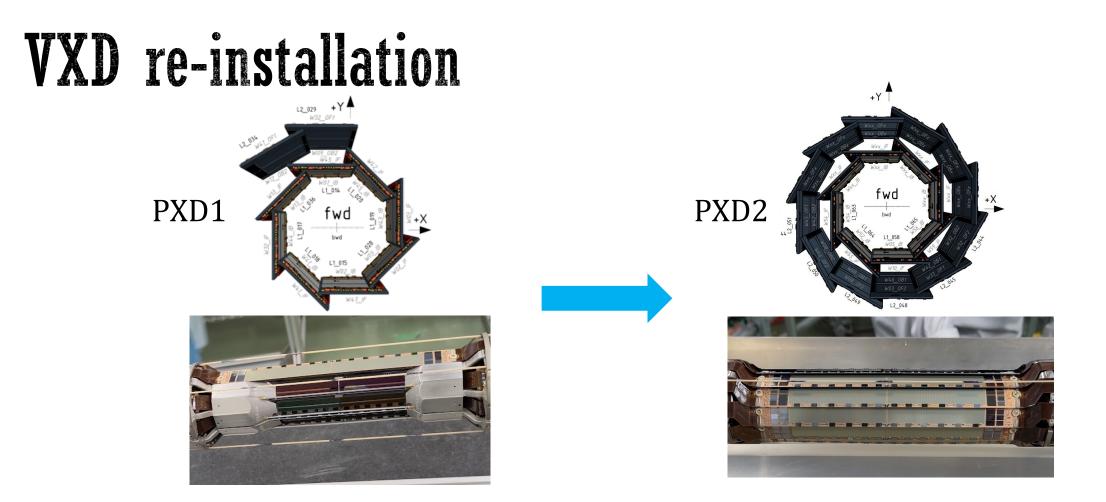


- Background extrapolation gives 0.35 Mrad/yr (8×10¹¹ n_{eq}/cm²/yr) of radiation dose (NIEL)
- SVD has good safety margin of 2 even after 10 years' operation at target luminosity, considering the 6 Mrad limit



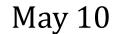
VXD reinstallation during Long Shutdown 1





- Replace PXD1 with PXD2 whose 2nd layer is fully installed
- Intense hardware activities on the SVD for the VXD uninstallation and reinstallation



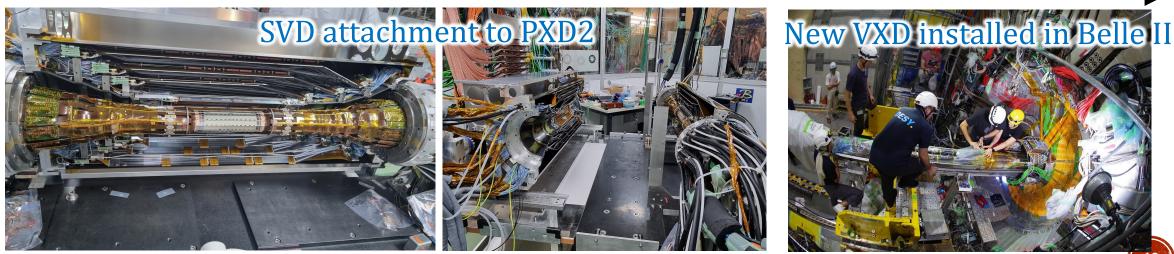






July 28

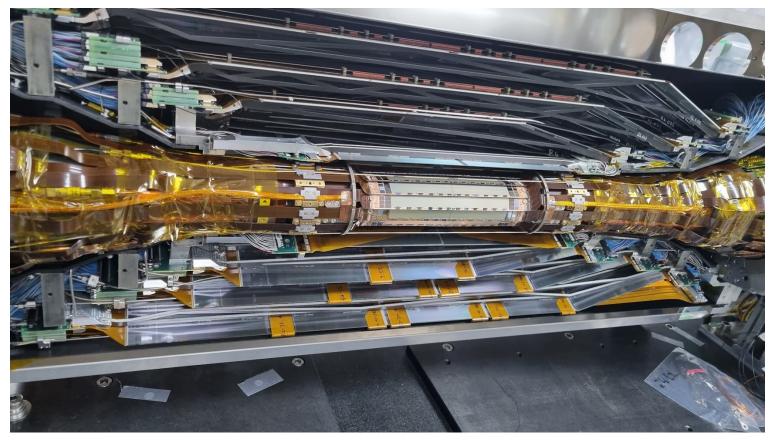
June 20~21





VXD re-installation

- VXD now re-assembled in Belle II successfully
- No problems found in during new VXD commissioning in the clean room
- Functional tests & commissioning with cosmic in September





Summary

- SVD has been taking data in Belle II since March 2019 with high quality
 - Excellent performance as expected
 - Effects on radiation damage observed, but no influence on performance yet
- Background extrapolation to target luminosity shows radiation dose is within safety margin, but hit occupancy could exceed our limit
 - VXD upgrade is under discussion
- During the Long Shutdown 1, new VXD with the complete PXD2 and the current SVD is re-assembled
 - Commissioning with cosmic in September
 - Plan to resume data taking in December
- SVD technical paper:
 - https://iopscience.iop.org/article/10.1088/1748-0221/17/11/P11042/pdf

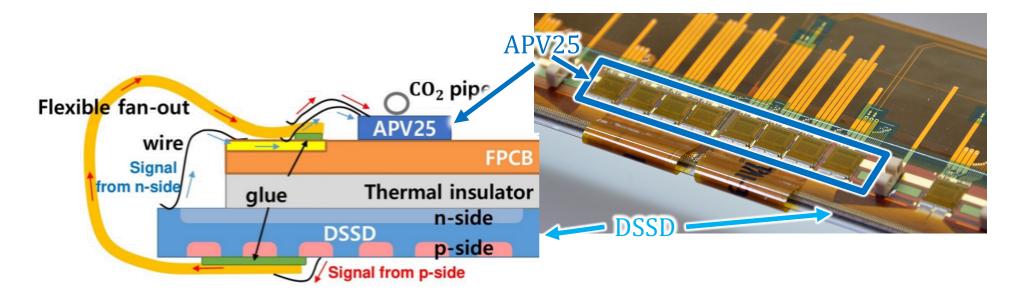


BACK UP



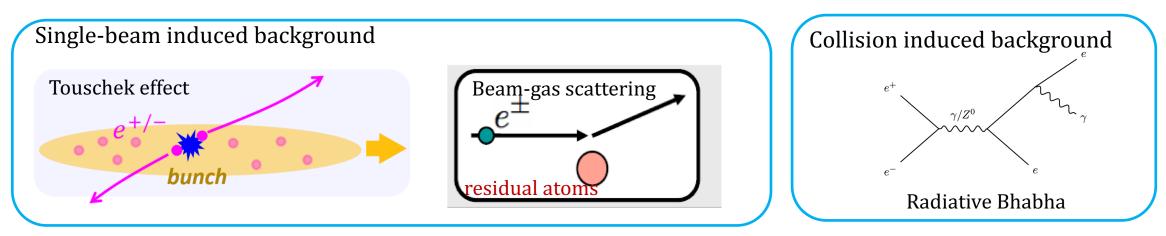
Chip-on-sensor concept

- Origami chip-on-sensor concept:
 - Shorter signal propagation length to reduce capacitance and noise
 - Two-phase CO₂ (-20 °C) cooling





Background sources

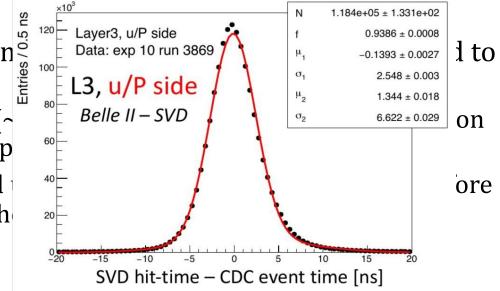


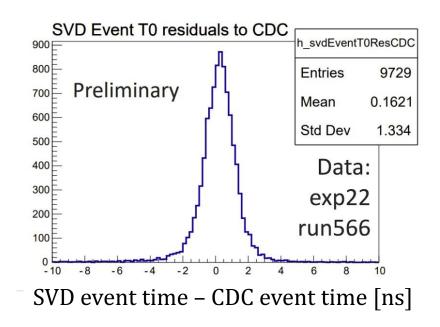
- Off-orbit particles hits beam pipe or detector materials and create showers
- Radiation damage
 - increasing leakage current, strip noise & changing depletion voltage
- High instantaneous hit occupancy
 - can degrade tracking performance



SVD event time

- SVD Event time con tracks
 - Same resolution (~ w.r.t. the one comp
 - Allowing to speed cope with the high

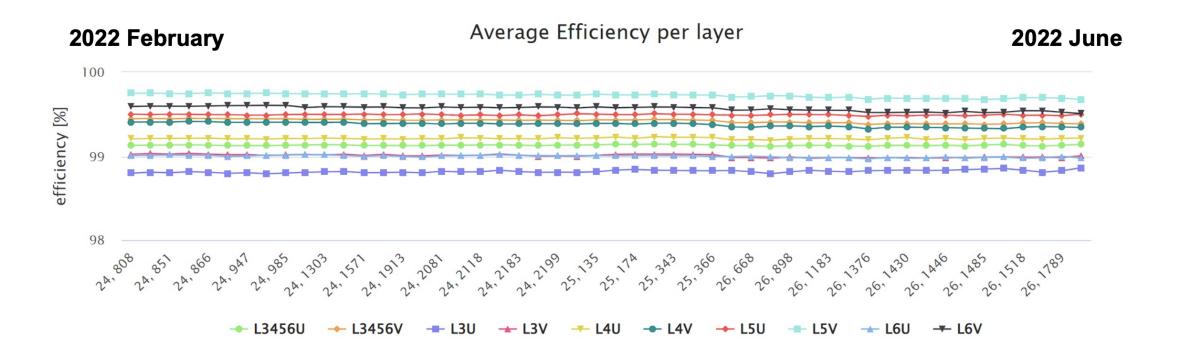






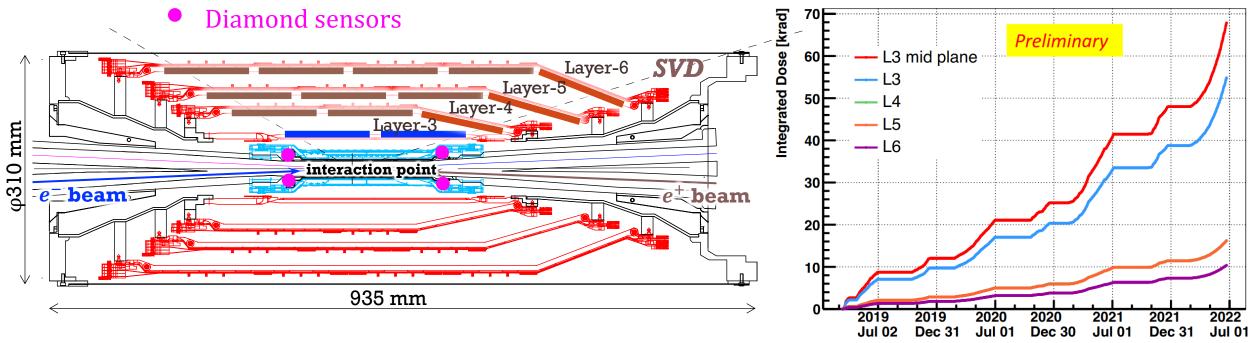
Efficiency

Hit efficiency is very high and stable in time



Radiation dose

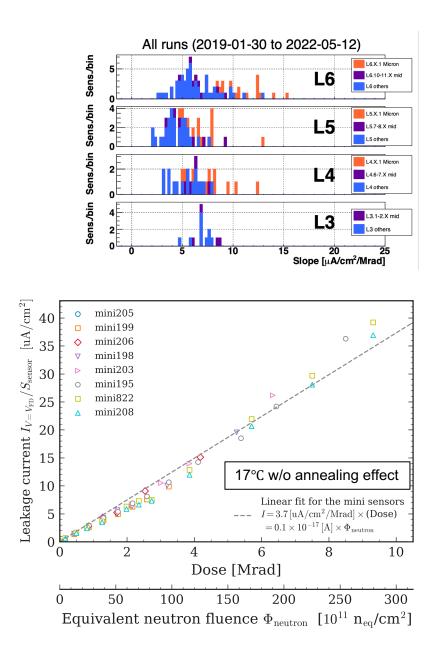
Constantly monitored using diamond sensors





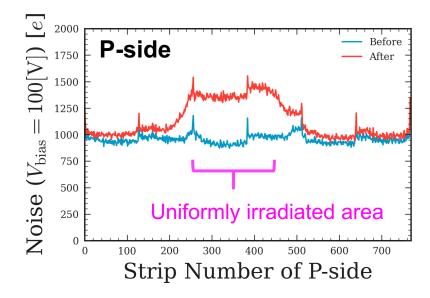
Leakage current

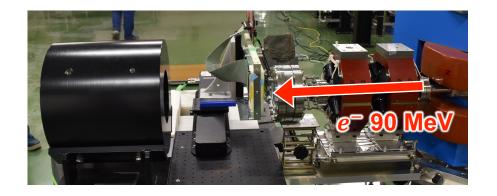
- Damage constant [µA/cm²/Mrad] ranges from 4~8 for sensors operated at different temperature 10~26 °C
- Irradiation campaign gives 2.2 for sensors radiated at 24 °C after annealing
- Babar sensors operated at 27 °C has a damage constant of 2
 - NIMA 729, 615-701, 2013
- Good consistence for different measurement



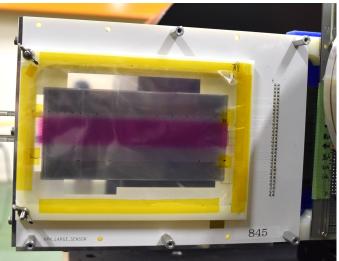
Strip noise

In the irradiation of 10 Mrad with annealing, noise increase is ~40%



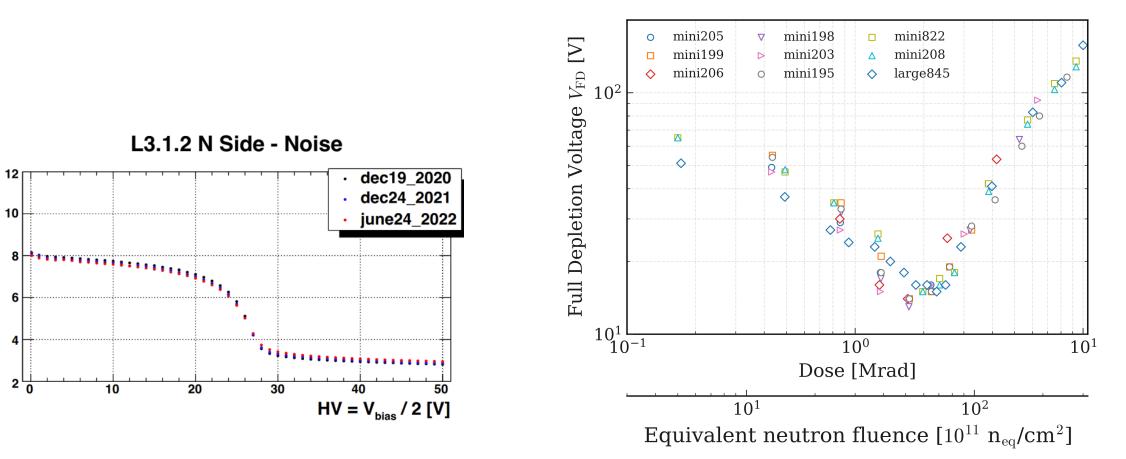


Uniformly irradiated area





Depletion voltage



12

10

8

6

Avg. noise n-side [ADC]